IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

SHEET 1 of 13

FIG. 1A

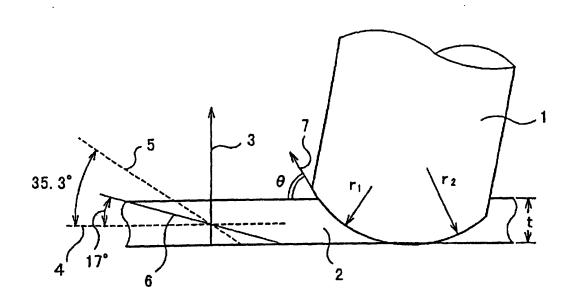
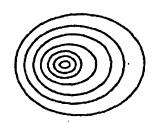


FIG. 1B

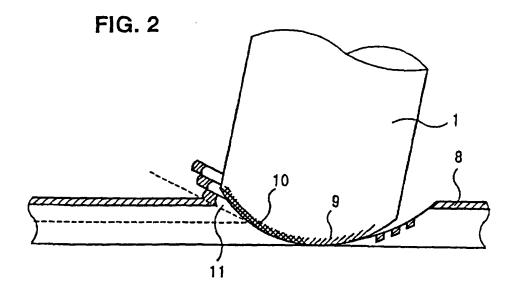


IMPROVED TIP PORTION

**INVENTOR(S):** TAKEMOTO ETAL

SHEET 2 of 13

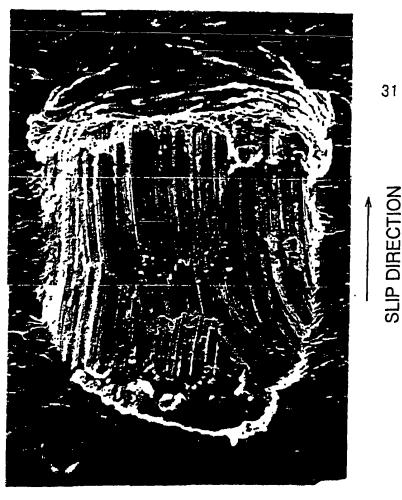
APPLICATION SERIAL NO: N/A



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INVENTOR(S): TAKEMOTO ETAL
APPLICATION SERIAL NO: N/A

SHEET 3 of 13

## FIG. 3



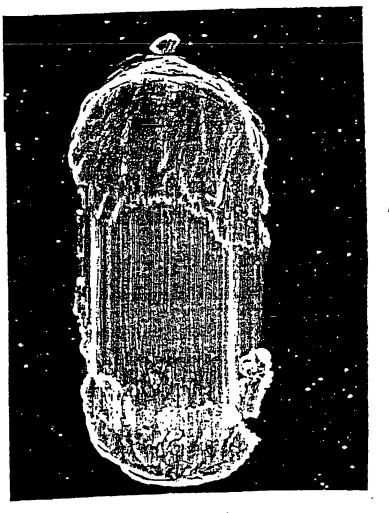
 $5 \mu m$ 

APPLN. FILING DATE: AUGUST 22, 2003
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INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A
SHEET 4

SHEET 4 of 13

SLIP DIRECTION

FIG. 4



10 μ m

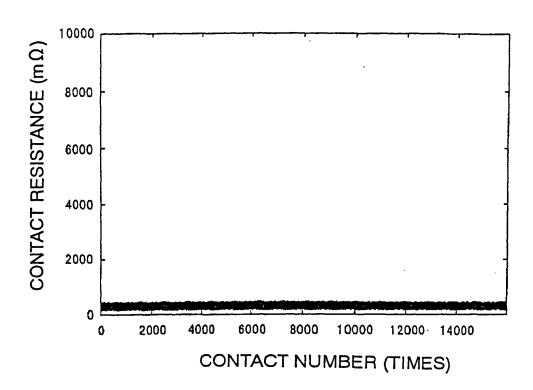
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

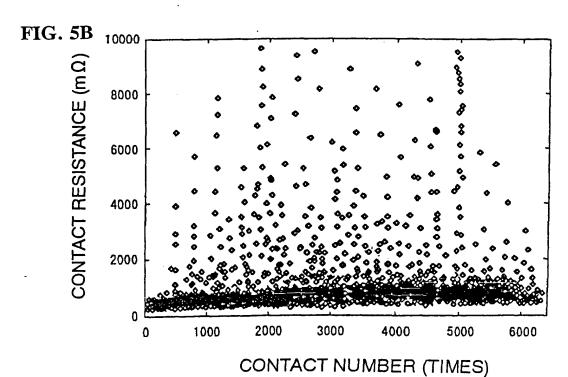
IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

SHEET 5 of 13

FIG. 5A



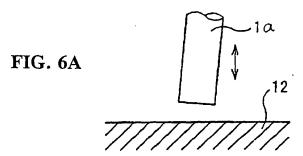


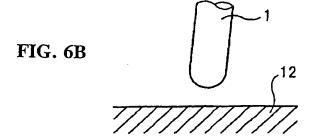
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

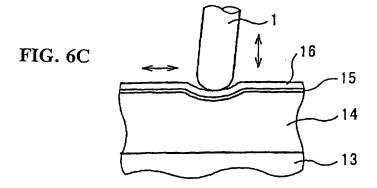
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SHEET 6 of 13







TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

SHEET 7 of 13

FIG. 7

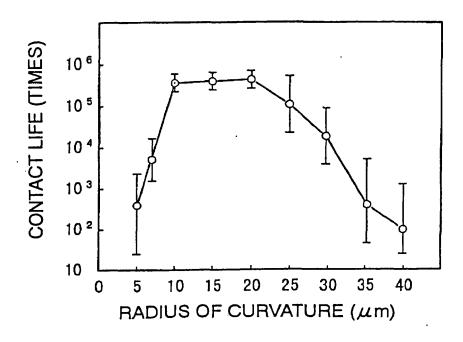
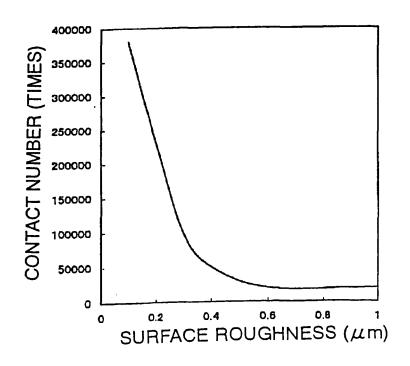


FIG. 8



TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

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SHEET 8 of 13

FIG. 9A

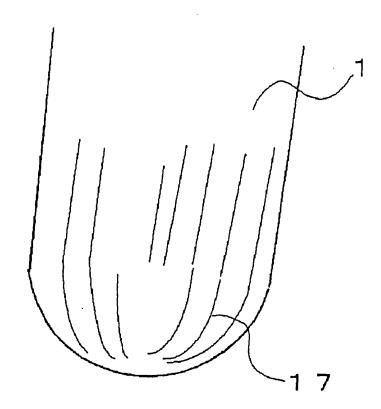
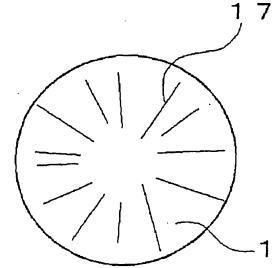


FIG. 9B



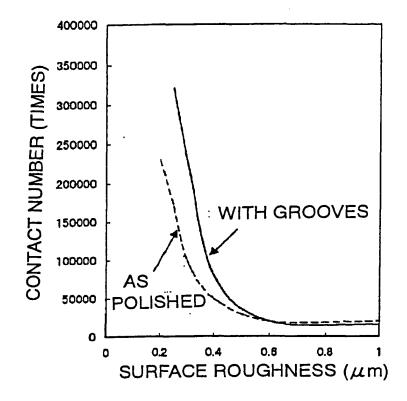
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

SHEET 9 of 13

FIG. 10



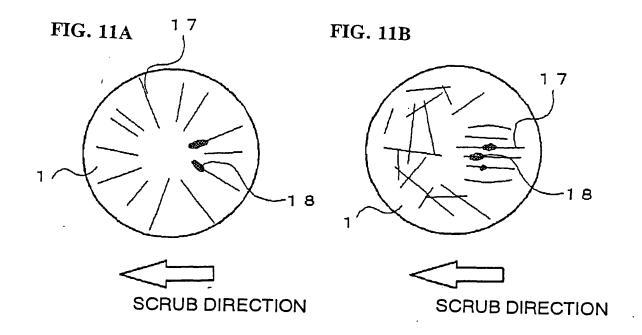
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

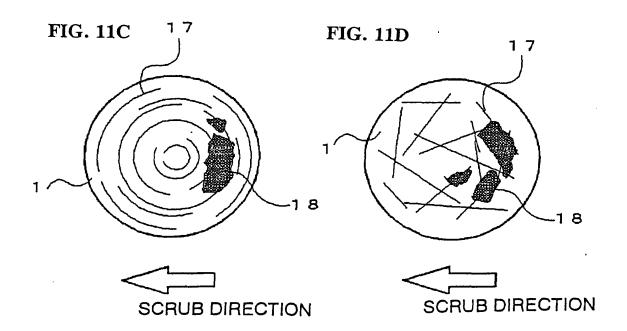
IMPROVED TIP PORTION.

**INVENTOR(S):** TAKEMOTO ETAL

APPLICATION SERIAL NO: N/A

**SHEET 10 of 13** 



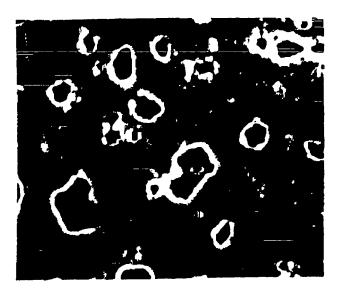


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INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

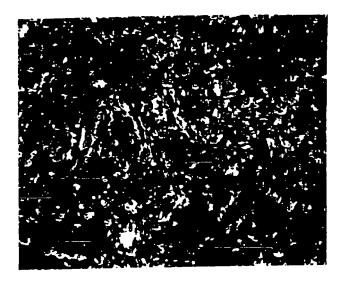
**SHEET 11 of 13** 

FIG. 12A



 $1 \mu m$ 

FIG. 12B

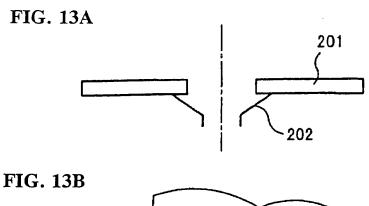


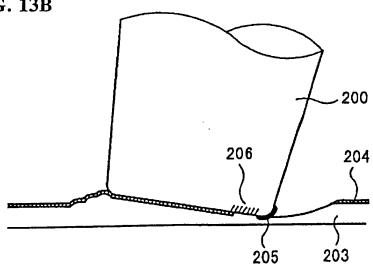
 $1 \mu m$ 

IMPROVED TIP PORTION

**INVENTOR(S):** TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

**SHEET 12 of 13** 





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TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

Inventor(s): Takemoto etal Application Serial No: N/A

**SHEET 13 of 13** 

FIG. 14

